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Group members:

C. Da Via' (100% research time), A. Kok (PhD 100%), A. Karpenko (PhD 50%), J. Hasi (PhD 100%), M. Kuhnke (TMR fellow 100%), S. Watts (10%)

Current Activities:

Characterisation of irradiated silicon devices at room and cryogenic temperatures using X-rays (CCE,  $V_{fd}$ ), minority carrier lifetime and DLTS (4-300K). Processing of defect engineered (silicon oxygen dimer) material. Processing and testing of 3D silicon detectors (Stanford). Variable temperature (80-1000 K) gamma irradiation. Material and device simulation using in-house developed software.

Field of interest:

Defect engineered silicon  
Device structure  
Basic studies/Simulation

Available resources:

Gamma  $^{60}\text{Co}$  Cell  
Liquid He DLTS system  
X-ray Liquid Nitrogen Multi-Channel Analyser system  
Minority carrier lifetime measurement setup  
Simulation software